- **EPIC™** (Enhanced-Performance Implanted **CMOS) Process**
- Packaged in Plastic Small-Outline **Transistor Package**

DBV PACKAGE (TOP VIEW) Vcc Α **GND**

NC - No internal connection

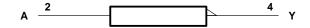
description

The SN74AHCT1G04 contains one gate. The device performs the Boolean function $Y = \overline{A}$. The SN74AHCT1G04 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

INPUT A	OUTPUT Y
Н	L
L	Н

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	V
VIH	High-level input voltage	2		V
V_{IL}	Low-level input voltage		0.8	V
٧ _I	Input voltage	0	5.5	V
٧o	Output voltage	0	VCC	V
IOH	High-level output current		-8	mA
loL	Low-level output current		8	mA
$\Delta t/\Delta v$	Input transition rise or fall rate		20	ns/V
T _A	Operating free-air temperature	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	vcc	T _A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX	IVIIIN	IVIAA	UNII
Vall	$I_{OH} = -50 \mu A$	4.5 V	4.4	4.5		4.4		V
VOH	$I_{OH} = -8 \text{ mA}$	4.5 V	3.94			3.8		
Va	$I_{OL} = 50 \mu A$	4.5 V			0.1		0.1	٧
VOL	$I_{OL} = 8 \text{ mA}$	4.5 V			0.36		0.44	
lį	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2		20	μΑ
Δl _{CC} ‡	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35		1.5	mA
C _i	$V_I = V_{CC}$ or GND	5 V		4	10		10	pF

 $^{^{\}ddagger}$ This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V $_{
m CC}$.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 25 millimeters.

PRODUCT PREVIEW

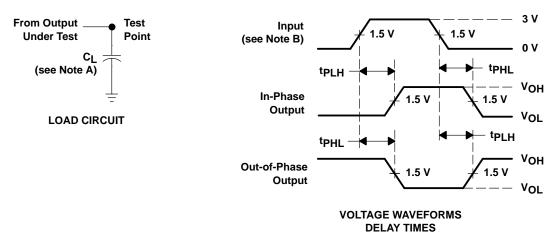
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO (OUTPUT)	то	LOAD	T _A = 25°C			MIN	MAX	UNIT		
		CAPACITANCE	MIN	TYP	MAX	IVIIIN	WAX	UNIT			
^t PLH	А	Y	V	A V	C 15 pE		4.7	6.7	1	7.5	20
^t PHL			C _L = 15 pF		4.7	6.7	1	7.5	ns		
^t PLH	^	Y	V C:	C 50 pF		5.5	7.7	1	8.5	20	
t _{PHL}	А		C _L = 50 pF		5.5	7.7	1	8.5	ns		

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CO	NDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load,	f = 1 MHz	14	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f = 3 \ ns$, $t_f = 3 \ ns$.
- C. The output is measured with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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